



### **Features**

- · 100% UIS + R<sub>g</sub> Tested
- Avalanche Rated
- · Reliable and Rugged
- Lead Free and Green Devices Available (RoHS Compliant)

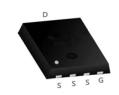
### **Applications**

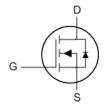
 Power Management in Notebook Computer, Portable Equipment and Battery Powered Systems.

### **Product Summery**

BVDSS	RDSON	ID
25V	$3.4m\Omega_{(max.)}$	70A

### DFN3.3x3.3-8-EP Pin Configuration





## Absolute Maximum Ratings (T<sub>A</sub> = 25°C Unless Otherwise Noted)

Symbol	Parameter	Rating	Unit		
Common	Ratings				
V <sub>DSS</sub>	Drain-Source Voltage	25	_ v		
V <sub>GSS</sub>	Gate-Source Voltage		±12	<b>¬</b> ′	
T <sub>J</sub>	Maximum Junction Temperature		150	°C	
T <sub>STG</sub>	Storage Temperature Range		-55 to 150		
I <sub>S</sub>	Diode Continuous Forward Current	T <sub>C</sub> =25°C	70 <sup>a</sup>		
	Continuous Drain Current	T <sub>C</sub> =25°C	70 <sup>a</sup>	$\Box$	
l I <sub>D</sub>	Continuous Diam Current	T <sub>C</sub> =100°C	60	7 ^	
I <sub>DM</sub>	Pulsed Drain Current	T <sub>C</sub> =25°C	200 <sup>b</sup>	200 <sup>b</sup>	
В	Maximum Dayor Diggination	T <sub>C</sub> =25°C	62.5	w	
P <sub>D</sub>	Maximum Power Dissipation	T <sub>C</sub> =100°C	25	ן יי ן	
R <sub>θJC</sub>	Thermal Resistance-Junction to Case Steady State		2	°C/W	
	Continuous Drain Current	T <sub>A</sub> =25°C	20	A	
l I <sub>D</sub>	Continuous Drain Current	T <sub>A</sub> =70°C	16	7 ^	
Б	Maximum Dayon Discination	T <sub>A</sub> =25°C	1.78	l w	
P <sub>D</sub>	Maximum Power Dissipation	T <sub>A</sub> =70°C	1.14		
Б	Thermal Desistance Junction to Ambient	t ≤ 10s	35	°C/W	
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	Steady State	70		
I <sub>AS</sub> <sup>c</sup>	Avalanche Current, Single pulse L=0.1mH		50	Α	
E <sub>AS</sub> <sup>c</sup>	Avalanche Energy, Single pulse L=0.1mH		125	mJ	

Note a : Package is limited by 50A.

Note b: Pulse width is limited by maximum junction temperature.

Note c : UIS tested and pulse width is limited by maximum junction temperature  $150^{\circ}$ C (initial temperature  $T_J = 25^{\circ}$ C).



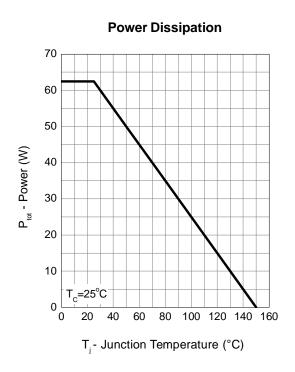
# **Electrical Characteristics** (T<sub>A</sub> = 25°C Unless Otherwise Noted)

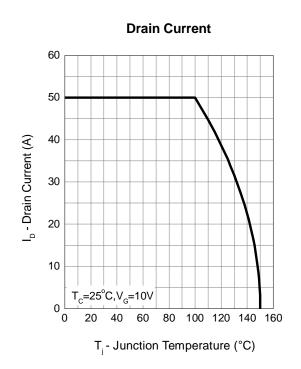
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Static Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250μA	25	-	-	V
	Zoro Coto Voltago Prain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V	-	-	1	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	T <sub>J</sub> =85°C	-	-	30	μΑ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{DS}=250\mu A$	0.5	0.8	1.1	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 12V, V_{DS}=0V$	-	-	±10	μΑ
		V <sub>GS</sub> =4.5V, I <sub>DS</sub> =20A	-	2.5	3.4	
R <sub>DS(ON)</sub> <sup>d</sup>	Drain-Source On-state Resistance	T <sub>J</sub> =125°C	-	3.9	-	mΩ
		V <sub>GS</sub> =2.5V, I <sub>DS</sub> =20A	-	3.0	4.0	
Gfs	Forward Transconductance	$V_{DS}$ =5V, $I_{DS}$ =20A	-	74	-	S
Diode Cha	aracteristics					
$V_{SD}^{d}$	Diode Forward Voltage	I <sub>SD</sub> =20A, V <sub>GS</sub> =0V	ı	0.7	1.1	V
t <sub>rr</sub>	Reverse Recovery Time		-	14.8	-	
t <sub>a</sub>	Charge Time	1 200 dl /dt 1000///2	-	7.1	-	ns
t <sub>b</sub>	Discharge Time	$I_F$ =20A, $dI_{SD}/dt$ =100A/ $\mu$ s	-	7.7	-	
Q <sub>rr</sub>	Reverse Recovery Charge		-	3.9	-	nC
Dynamic	Characteristics <sup>e</sup>					
$R_{G}$	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1MHz$	-	0.85	-	Ω
C <sub>iss</sub>	Input Capacitance	$V_{GS}=0V$ ,	-	4920	-	
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =15V,	-	510	-	pF
$C_{rss}$	Reverse Transfer Capacitance	Frequency=1.0MHz	-	350	-	
t <sub>d(ON)</sub>	Turn-on Delay Time		-	16.6	31	
t <sub>r</sub>	Turn-on Rise Time	$V_{DD}=15V$ , $R_L=15\Omega$ ,	-	12.2	23	
t <sub>d(OFF)</sub>	Turn-off Delay Time	$I_{DS}$ =1A, $V_{GEN}$ =10V, $I_{CS}$ =6 $\Omega$	-	135	244	ns
t <sub>f</sub>	Turn-off Fall Time		-	48	87	
Gate Cha	rge Characteristics <sup>e</sup>			•	•	•
$Q_g$	Total Gate Charge	V <sub>DS</sub> =15V, V <sub>GS</sub> =4.5V, I <sub>DS</sub> =20A		47	66	
Qg	Total Gate Charge		ı	96	134	
$Q_{gth}$	Threshold Gate Charge	V <sub>DS</sub> =15V, V <sub>GS</sub> =10V,	-	2.75	3.8	nC
Q <sub>gs</sub>	Gate-Source Charge	I <sub>DS</sub> =20A	-	5.5	7.7	
$Q_{gd}$	Gate-Drain Charge		-	16	22	

Note d : Pulse test; pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. Note e : Guaranteed by design, not subject to production testing.

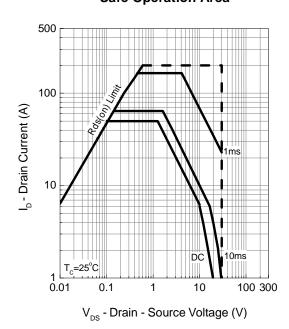


# **Typical Operating Characteristics**

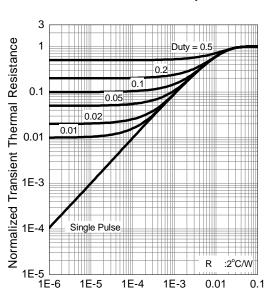




## Safe Operation Area



### **Thermal Transient Impedance**

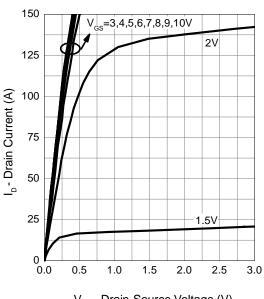


Square Wave Pulse Duration (sec)



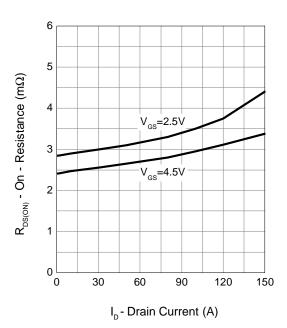
# Typical Operating Characteristics (Cont.)

### **Output Characteristics**

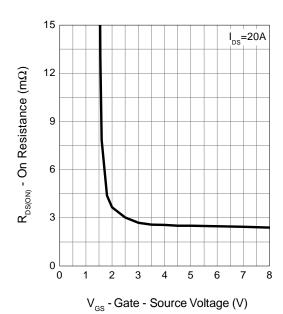


 $V_{\scriptscriptstyle DS}$  - Drain-Source Voltage (V)

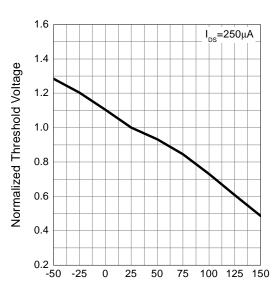
#### **Drain-Source On Resistance**



**Gate-Source On Resistance** 



### **Gate Threshold Voltage**

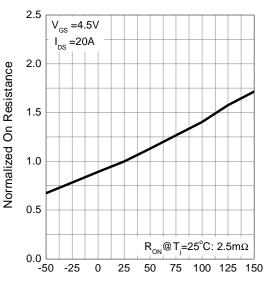


T<sub>i</sub> - Junction Temperature (°C)



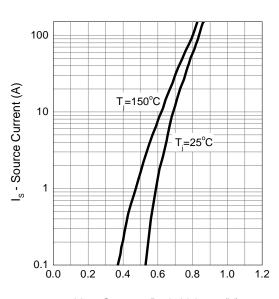
# **Typical Operating Characteristics (Cont.)**

#### **Drain-Source On Resistance**



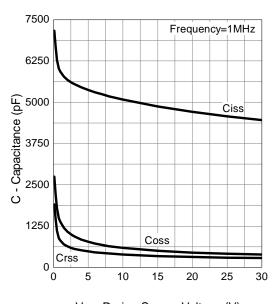
T<sub>i</sub> - Junction Temperature (°C)

#### Source-Drain Diode Forward



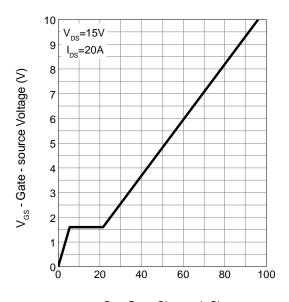
 $V_{SD}$  - Source - Drain Voltage (V)

### Capacitance



 $V_{\scriptscriptstyle DS}$  - Drain - Source Voltage (V)

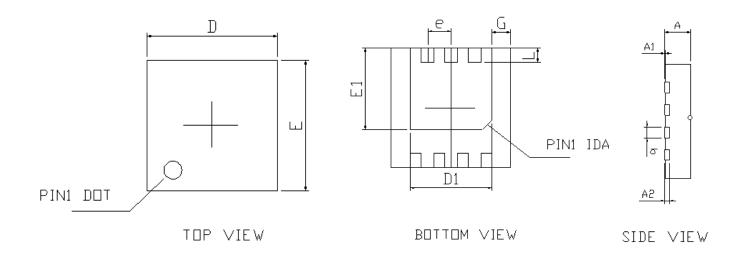
### **Gate Charge**



 $\mathbf{Q}_{_{\mathbf{G}}}$  - Gate Charge (nC)

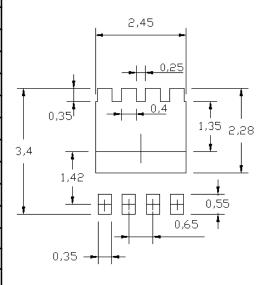


# DFN3.3x3.3B-8\_EP1-S



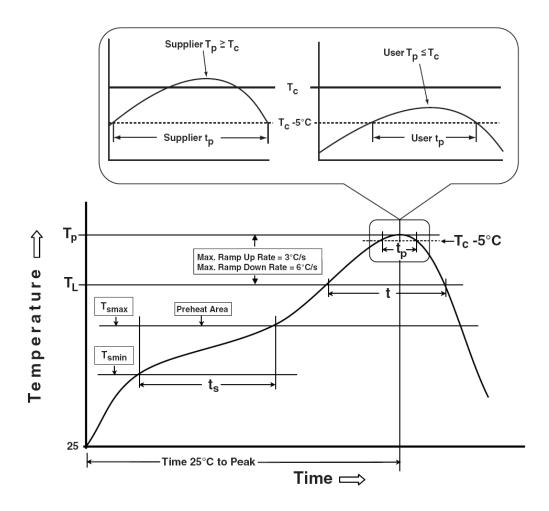
	DFN3.3x3.3B-8_EP1_S			
SYMBOLS	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
Α	0.700	0.800	0.028	0.032
A1	0.000	0.050	0.000	0.002
A2	0.100	0.250	0.004	0.010
b	0.240	0.350	0.009	0.014
D	3.150	3.400	0.124	0.134
D1	2.100	2.350	0.083	0.093
Е	3.150	3.400	0.124	0.134
E1	2.150	2.350	0.850	0.093
ē	0.600	0.700	0.024	0.028
G	0.475	0.575	0.019	0.023
L	0.350	0.450	0.014	0.018

### **RECOMMENDED LAND PATTERN**





## **Classification Profile**





## **Classification Reflow Profiles**

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly	
Preheat & Soak Temperature min (T <sub>smin</sub> ) Temperature max (T <sub>smax</sub> ) Time (T <sub>smin</sub> to T <sub>smax</sub> ) (t <sub>s</sub> )	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds	
Average ramp-up rate (T <sub>smax</sub> to T <sub>P</sub> )	3 °C/second max.	3°C/second max.	
Liquidous temperature (T <sub>L</sub> ) Time at liquidous (t <sub>L</sub> )	183 °C 60-150 seconds	217 °C 60-150 seconds	
Peak package body Temperature (T <sub>p</sub> )*	See Classification Temp in table 1	See Classification Temp in table 2	
Time $(t_P)^{**}$ within 5°C of the specified classification temperature $(T_c)$	20** seconds	30** seconds	
Average ramp-down rate (T <sub>p</sub> to T <sub>smax</sub> )	6 °C/second max.	6 °C/second max.	
Time 25°C to peak temperature 6 minutes max. 8 minutes max.			
* Tolerance for peak profile Temperature $(T_p)$ is defined as a supplier minimum and a user maximum. ** Tolerance for time at peak profile temperature $(t_p)$ is defined as a supplier minimum and a user maximum.			

Table 1. SnPb Eutectic Process – Classification Temperatures (Tc)

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm³ ³350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process - Classification Temperatures (Tc)

Package	Volume mm <sup>3</sup>	Volume mm <sup>3</sup>	Volume mm <sup>3</sup>
Thickness	<350	350-2000	>2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

# Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	1000 Hrs, 80% of VDS max @ Tjmax
HTGB	JESD-22, A108	1000 Hrs, 100% of VGS max @ Tjmax
PCT	JESD-22, A102	168 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -65°C~150°C



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